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M	AA	3,299,424	1/67	Vinding									
N	AB	3,852,755	12/74	Works et al.		_							
<b>γ</b> -	AC	4.075,632	2/21/78	Baldwin et al.			-						
~	AD	4,572,976	2/25/86	Fockens									
m	ΑE	4,656,463	4/7/87	Anders et al.									
h_	AF	4,700,179	10/87	Fancher		-							
m	AG	4,724,427	2/9/88	Carroll		-							
n	АН	4,743,864											
1	Al	4,800,543	1/89	Lyndon-James et al.		-	)						
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_	AR	"Micron Morning	Report", The	Idaho Statesman, July 16, 1993.									
	AS	*A Low-Power Spi	read Spectrum	CMOS RFIC for Radio Identifica	tion Applications, by	John R. Tutt	tle, Conferen	ice					
$\mid v \mid$		Proceedings from	n RF Expo W	est, pp. 216-222, March 22-24, 199	)4, San Jose, CA.								
v	АТ	AT Provisional Application, Serial No. 60/023,321, Filed July 30, 1996.											
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N	АА	4,81	6,839	3/89	Landt				_	-		
w	AB	4,82	7,395	5/89	Anders et	al.		_	-			
~	AC	4,85	3,705	8/89	Landt				_	-	_	
n	AD	4,85	4,328	8/8/89	Pollack				_	-		
n	AE	4,85	7,893	8/15/89	Carroll			/	-	-		
~	AF	4,86	2,160	8/29/89	Ekchian et	al.		_	_	_		
~	AG	4,87	0,419	9/26/89	Baldwin et	al.		_	_	_		
n	AH	4,88	8,591	12/19/89	Landt et a	<b>i.</b>				-		
w	AI	4,89	0,072	12/26/89	Espe et al.				_	-		-
N	AJ	4,91	2,471	3/27/90	Tyburski et	: al.			_	_	-	
	AK	4,92	6,182	5/15/90	Ohta et al.				_	_		
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~	AR		*CMOS Analog In	tegrated Circu	uits Based on	Weak Inversion Ope	ration", by Eric Vittoz	and Jean I	fellrath,	, IEEE J	lournal of	
			Solid State Circ	uits, Vol. SC-	12, No. 3, Ju	ne 19 <b>7</b> 7						
	AS		Mitsubishi Motors	Corporation	Web Page, 19	95			ū			
	AT		*Digital RF/ID En	hances GPS*,	by John R. T	uttle, Proceedings of	the Second Annual V	Vireless Sym	posium	, рр.406-	411,	
	-		February 15-18,	1994, Santa (	Clara, CA							
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W	AA	5,030,807	7/91	Landt et al.			_		
~	AB	5,075,691	12/91	Garay et al.		_	_		
n	AC	5,081,458	1/92	Meunier		_	_		
a	AD	5,086,389	2/4/92	Hassett et al.		_	ړ	,	
1	AE	5,122,687	6/92	Schmidt		_	7		
~	AF	5,128,938	7/92	Вотгаѕ		_	7		
へ	AG	5,130,668	7/92	Emslie et al.		_	/		
1	АН	5,134,085 -	7/28/92	Gilgen et al.	_	_	_		
~	Al	5,142,292	8/92	Chang		_	_		
1	LΑ	5,144,314	9/1/92	Malmberg et al.		-	7		
~	ΑK	5,151,624	9/92	Stegherr et al.		_	-		
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~	AS	"Micron RFID Co	ommunications	Protocol Manual," July 22, 1993, I	Pre-Release Version 0	.95, pp. 1-71	l <b>.</b>		
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N	АЛ	5,153	3,583	10/92	Murdoch	<u> </u>	( bu	_			
n	AB	5,16	4,985	11/17/92	Nysen et al.			_	7	•	
~	AC	5,175	5,774	12/29/92	Truax et al.		(	_	ر		
1	AD	5,200	5,609	4/27/93	Mijuskovic		_	_	ر		
N	AE	5,218	B,343	6/8/93	Stobbe et al.		)	-	-		
n	AF	5,23	1,273	7/93	Caswel		_	_	/		
5	AG	5,25	2,979	10/12/93	Nysen		1	_			
n	АН	5,27	2,367	12/21/93	Dennison et al.				_		
~	Al	5,28	7,112	2/15/94	Schuermann		-	_	_		
	AJ	5,29	4,928	3/15/94	Cooper et al.		-	_	_		
~	AK	5,300	0,875	4/5/89	Tuttle		_		-		
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~	AA	5,311	1,186	5/94	Utsu et al.			_	-		
~	AB	5,323	3,150	6/21/94	Tuttle				_ [		
سبن	AC	5,355	5,513	10/94	Clarke et al.		ノ		-		
v	AD	5,365	5,551	11/15/94	Snodgrass et al.		ر		-		
5	AE	5,374	1,930	12/20/94	Schuermann			_	-		
<u></u>	AF	5,394	1,444	2/95	Silvey et al.				-		
~،	AG	5,400	5,263	4/11/95	Tuttle				-		
$\mathcal{N}$	AH	5,412	2,351	5/95	Nystrom et al.		~	_	_		
in-	. AI	5,420	0,757	5/30/95	Eberhardt et al.		_		-		
u	AJ.	5,430	0,441	7/95	Bickley et al.			_	_		
a	- AK	5,444	1,223	8/95	Blama			_			
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~~/	AA	5,446	,761	8/95	Nag et al.		7	-		
<b>~</b>	AB	5,448	,110	9/95	Tuttle et al.		1	ĺ		
~	- AC	5,448	,242	9/5/95	Sharpe et al.		7	(		
~~	AD	5,448	,2772	9/95	Grandfield		)	1		
N	AE	5,450	,087	9/95	Hurta et al.	•	1	)		
4	AF	5,461	,385	10/24/95	Armstrong		)	_		
· ·	AG	5,471	,212	11/28/95	Sharpe et al.		-	_		
u	ΑН	5,478	,991	12/95	Watanabe et al.		7	_		
1	Al	5,489	,546	2/6/96	Ahmad et al.		_	_		
w	ΑJ	5,499	,214	3/96	Mori et al.		)	).		
2	AK	5,500	,650	3/19/96	Snodgrass et al.			-		
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N	AA	5,525	5,992	6/96	Froschermeier			)	1		
~	AB	5,541	,583	7/96	Mandelbaum			_	)		
v	AC	5,541	,585	7/96	Duhame et al.			_	1		
~	– AD	5,568	,512	10/96	Rotzoli						
N	AE	5,606	,323	2/97	Heinrich et al.			1	)		
a	AF	5,621	,412	4/15/97	Sharpe et al.			-	)		
~	AG	5,623	,224	4/22/97	Yamada et al.			_	)		
n	ΑН	5,649	,296	7/15/97	MacLellan et al.			_	1		
2	Al	5,657	,359	8/97	Sakae et al.			_	1		
	ĄJ	5,677	,667	10/14/97	Lesesky et al.			_	7		
1	AK	5,686	,864	11/97	Martin et al.			_	7		
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~	AC	5,719	,550	2/17/98	Bloch et al.		•	1	_		
~	AD	5,721	,678	2/24/98	Widl			1	_		
~	AE	5,721	,783	2/98	Anderson				_		•
v	AF	5,726	,630	3/10/98	Marsh et al.		: <del></del>	_	_		
~	AG	5,815	,042	9/98	Chow et al.						
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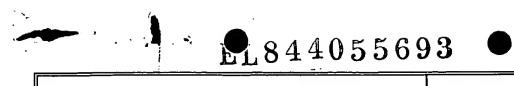
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n	AC	3,924,320	12/1975	Altman et al.	ERO	D_	R	ECEI	<b>VED</b>
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n	АН	4,190,838	02/1980	Kemp		343	18				
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· 		No. 4, April 1991, pages 169-171  No. 4, April 1991, pages 169-171  MAR 0 5 2002  GROUP 3600									
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~	AB	4,942	2,393	07/17/90	Waraksa et al.		340	825.72			
~	AC	5,235	5,326	08/10/93	Beigel et al.		340	825.54	54 _		
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